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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/945,171	SMITH ET AL.	
Examiner	Art Unit	
Erin M. File	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	295	1/11/2007	EMF
375	296	1/11/2007	EMF
375	297	1/11/2007	EMF
327	291	1/11/2007	EMF
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH S		)
	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only—see search history printout)	1/11/2007	EMF
PLUS Search	1/12/2007	EMF
Consultation on 112 6 <sup>th</sup> and 2 <sup>nd</sup> isssues with Reinhard Eisenzopf	1/18/2007	EMF .
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